

[54] ELECTRONIC SYSTEM TEST INSTRUMENT

[75] Inventor: Randall N. Eilert, Bothell, Wash.

[73] Assignee: John Fluke Mfg. Co., Inc., Everett, Wash.

[**] Term: 14 Years

[21] Appl. No.: 181,644

[22] Filed: Aug. 26, 1980

[52] U.S. Cl. D10/75; D14/106

[58] Field of Search D10/46, 75, 78; D14/105, 106, 100, 107; D18/7, 6, 4; 324/57, 115, 73 R, 156

[56] References Cited

U.S. PATENT DOCUMENTS

D. 196,509	10/1963	Schmidt	D10/75 X
D. 210,212	2/1968	Sanborn	D14/106
D. 212,783	11/1968	Yoshida	D18/7
D. 222,140	10/1971	Nakanishi	D18/7
D. 231,989	7/1974	Kitai	D18/7
D. 243,534	3/1977	Blesch	D14/106
D. 248,554	7/1978	Hawkins	D14/106
D. 257,146	9/1980	Valestin	D14/106

OTHER PUBLICATIONS

Hewlett-Packard Flyer—"HP-97 Calculator" on cover, 7/76.

Electronic Technician/Dealer-1/75, p. 42-Multimeter at top.

Primary Examiner—Nelson C. Holtje
Attorney, Agent, or Firm—Christensen, O'Connor, Johnson & Kindness

[57] CLAIM

The ornamental design for an electronic system test instrument, as shown and described.

DESCRIPTION

FIG. 1 is a top and right front perspective view of an electronic system test instrument showing my new design;

FIG. 2 is a front elevational view thereof;

FIG. 3 is a left side elevational view thereof;

FIG. 4 is a right side elevational view thereof;

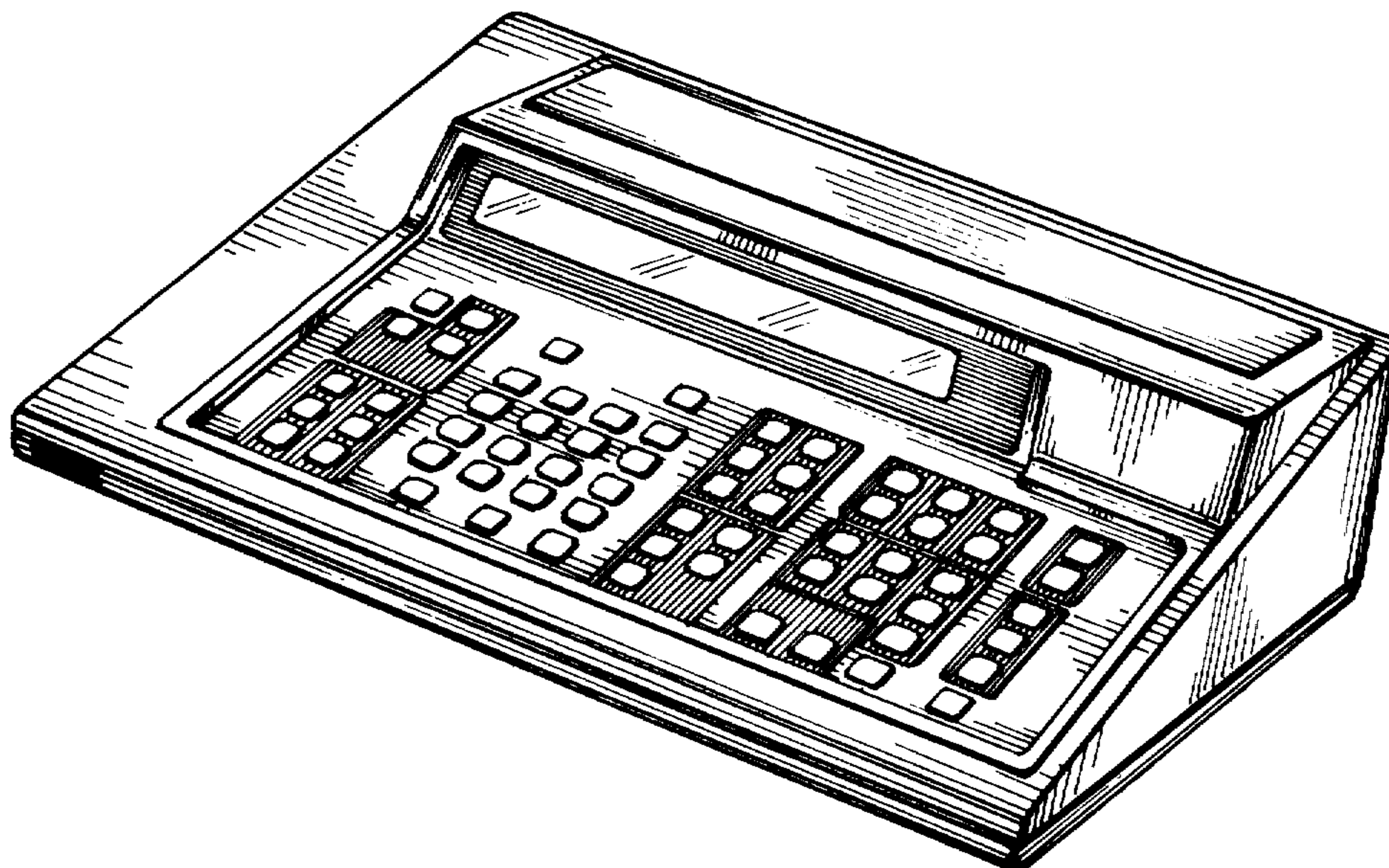
FIG. 5 is a top plan view thereof;

FIG. 6 is a bottom plan view thereof;

FIG. 7 is a left front perspective view of a second embodiment of my new design of FIGS. 1-6;

FIG. 8 is a left front perspective view of a third embodiment of my new design of FIGS. 1-6;

FIG. 9 is a left side perspective view of a fourth embodiment of my new design of FIGS. 1-6.



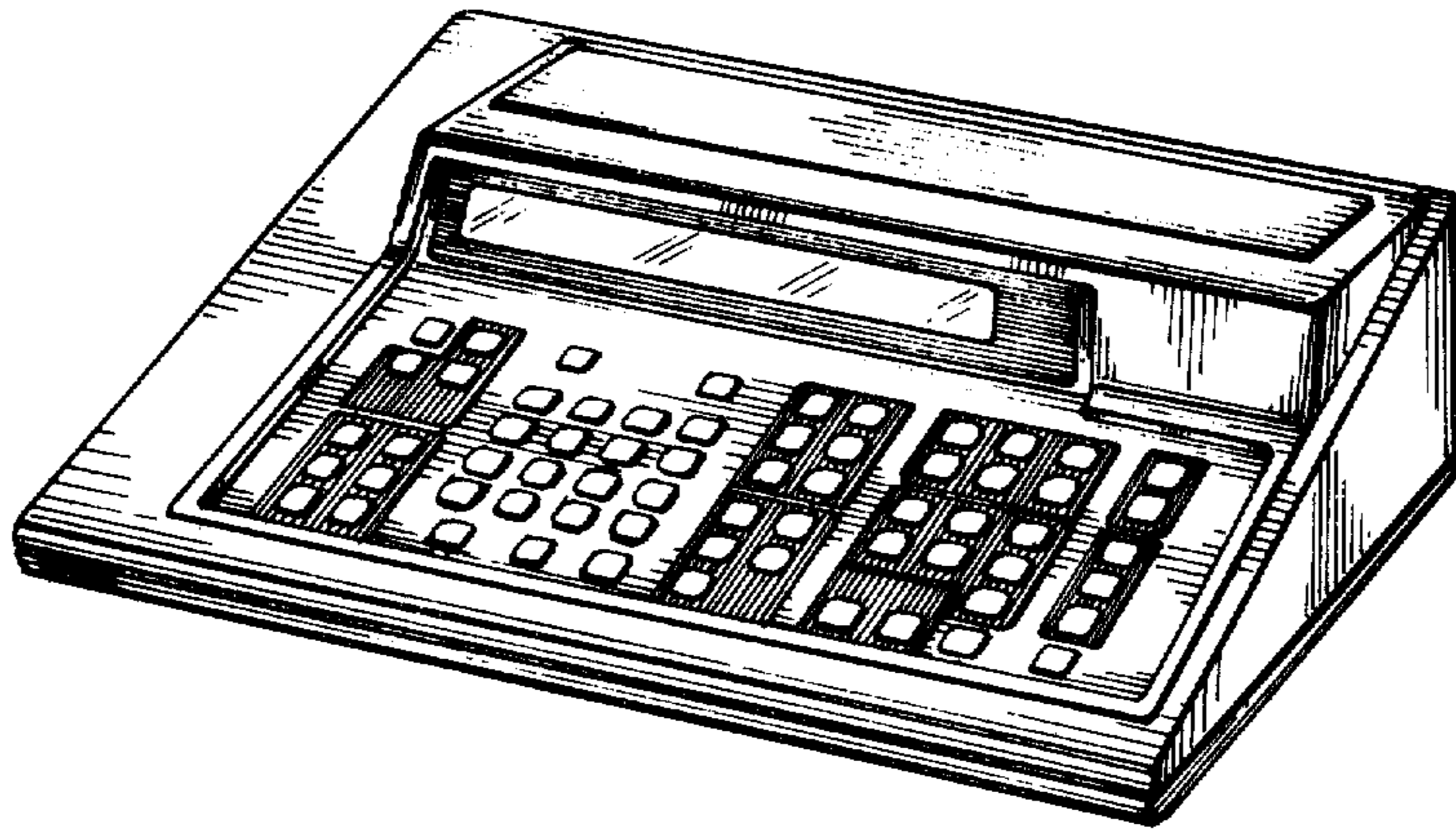


Fig. 1.

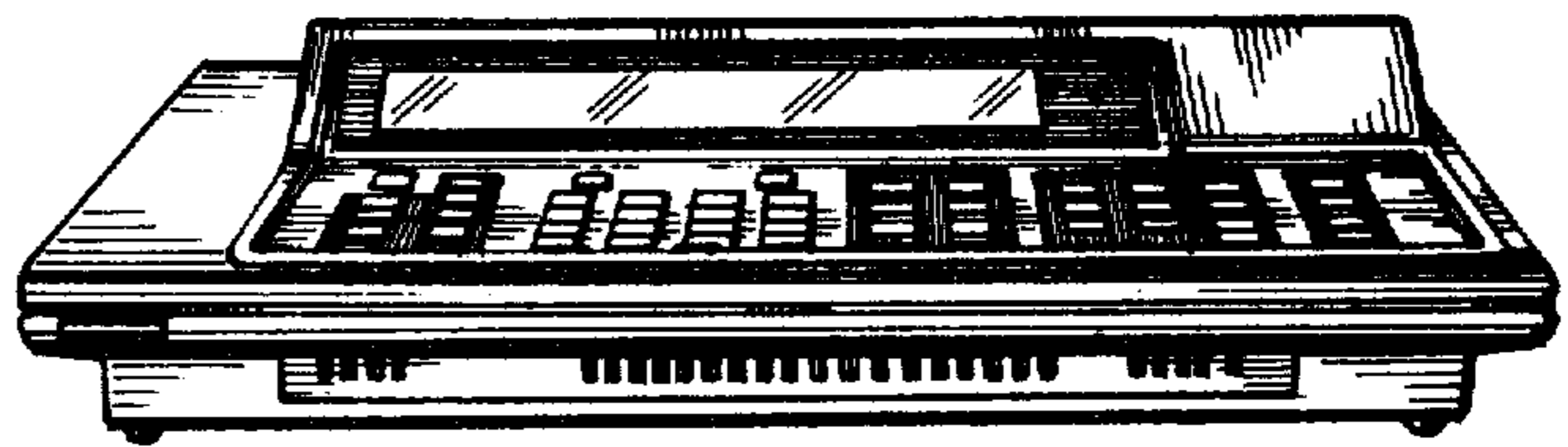


Fig. 2.

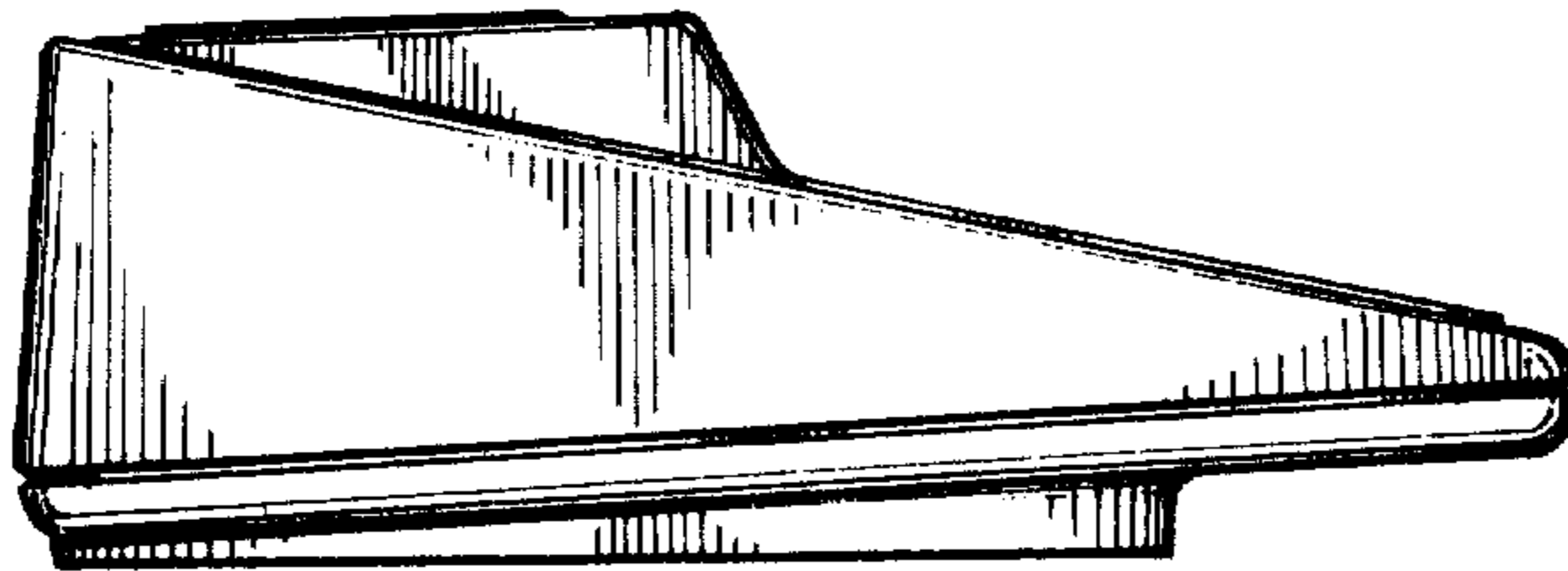


Fig. 3.

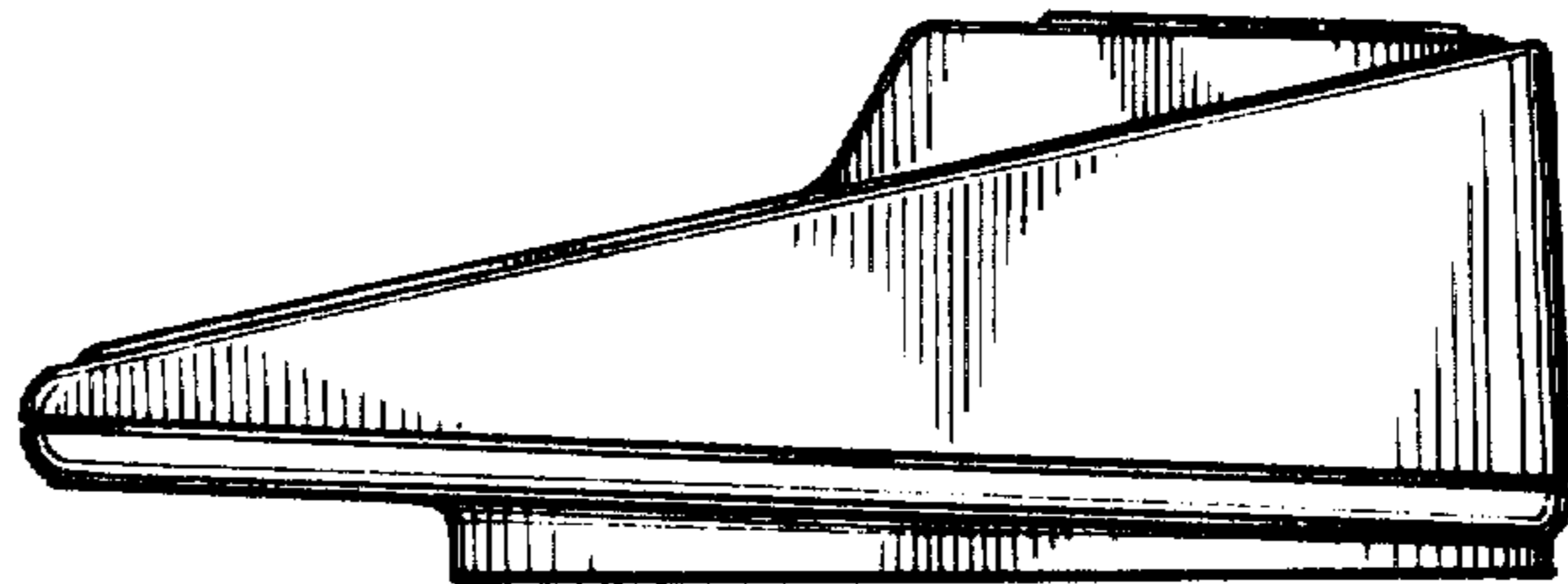


Fig. 4.

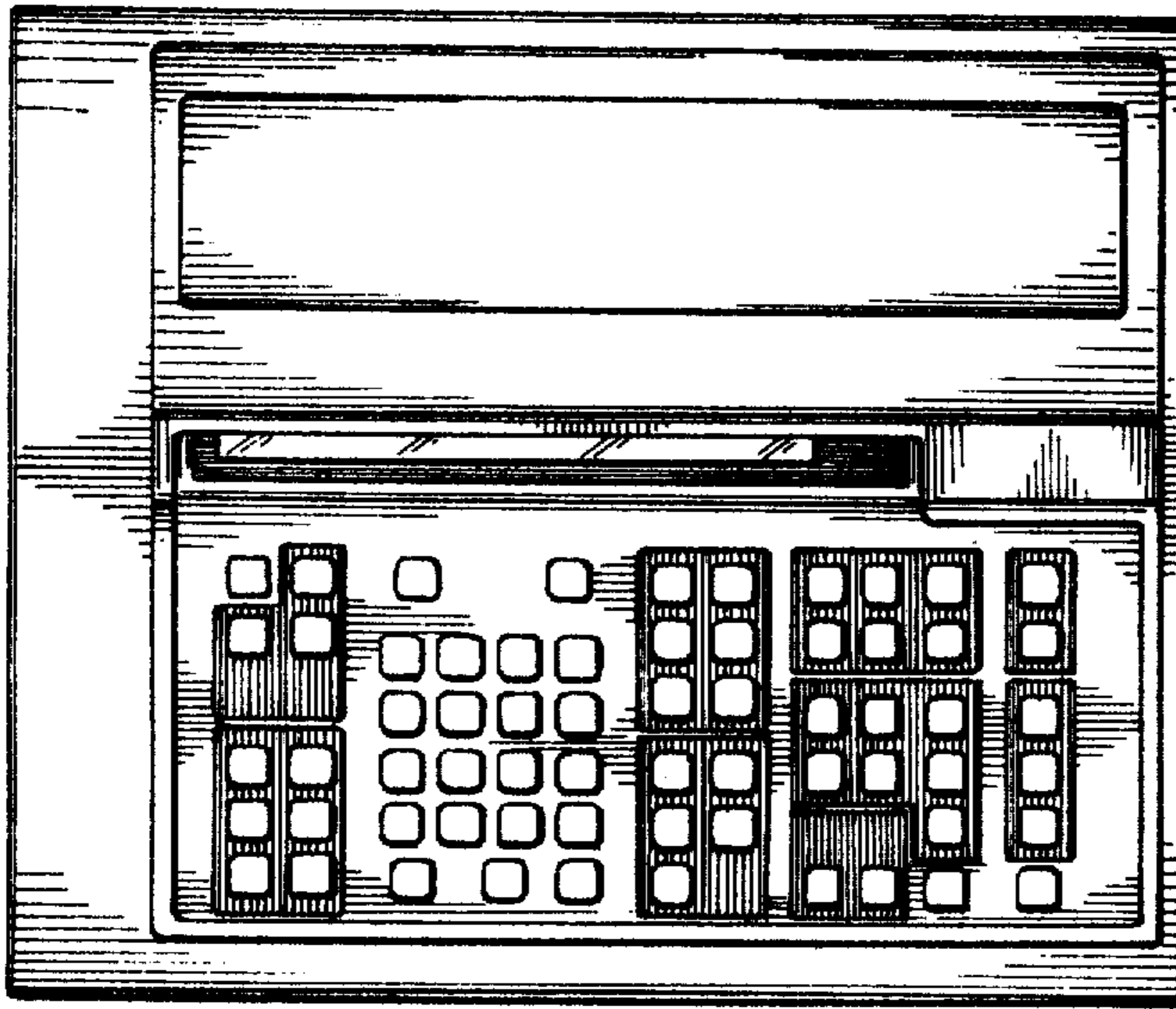


Fig. 5.

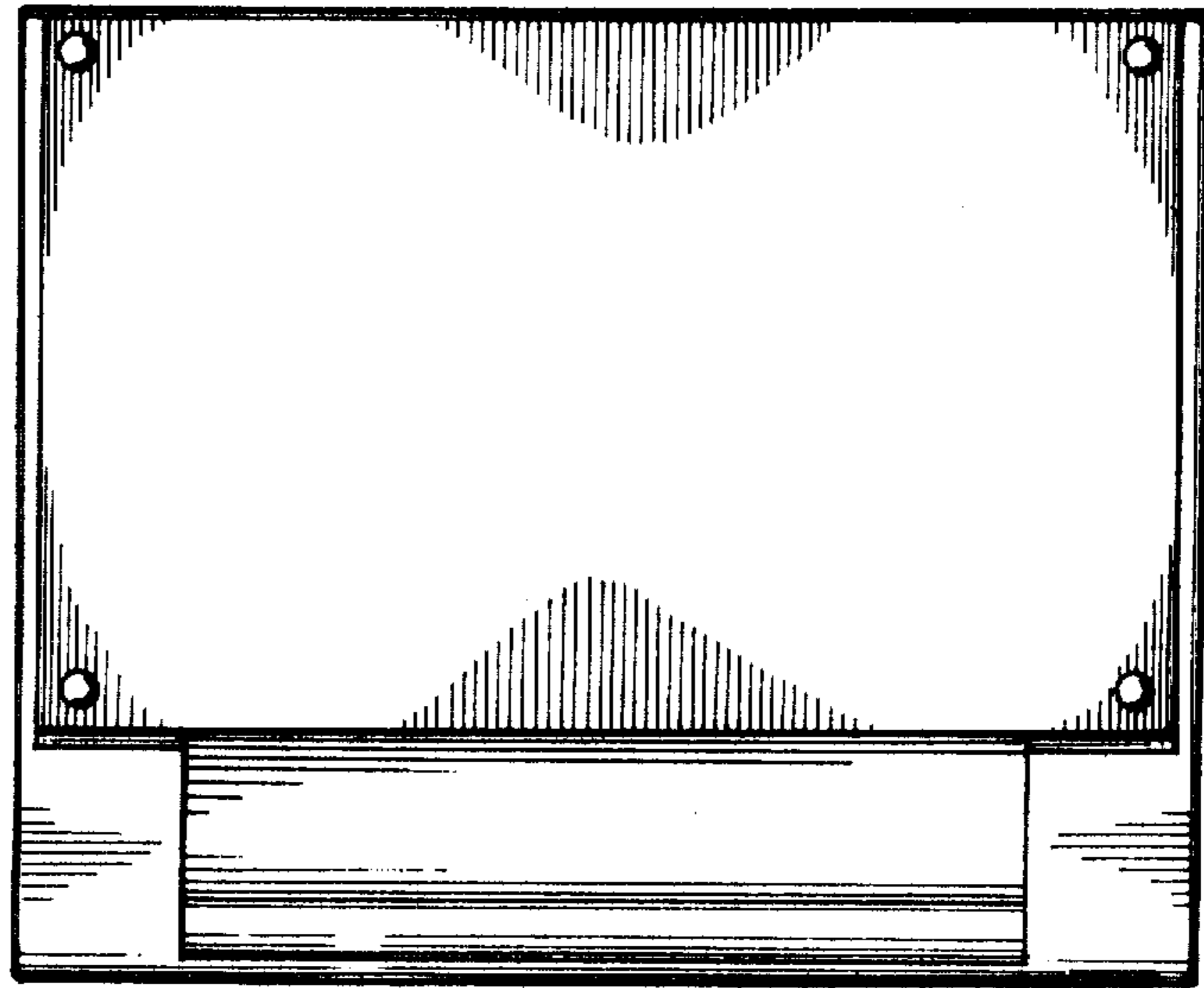


Fig. 6.

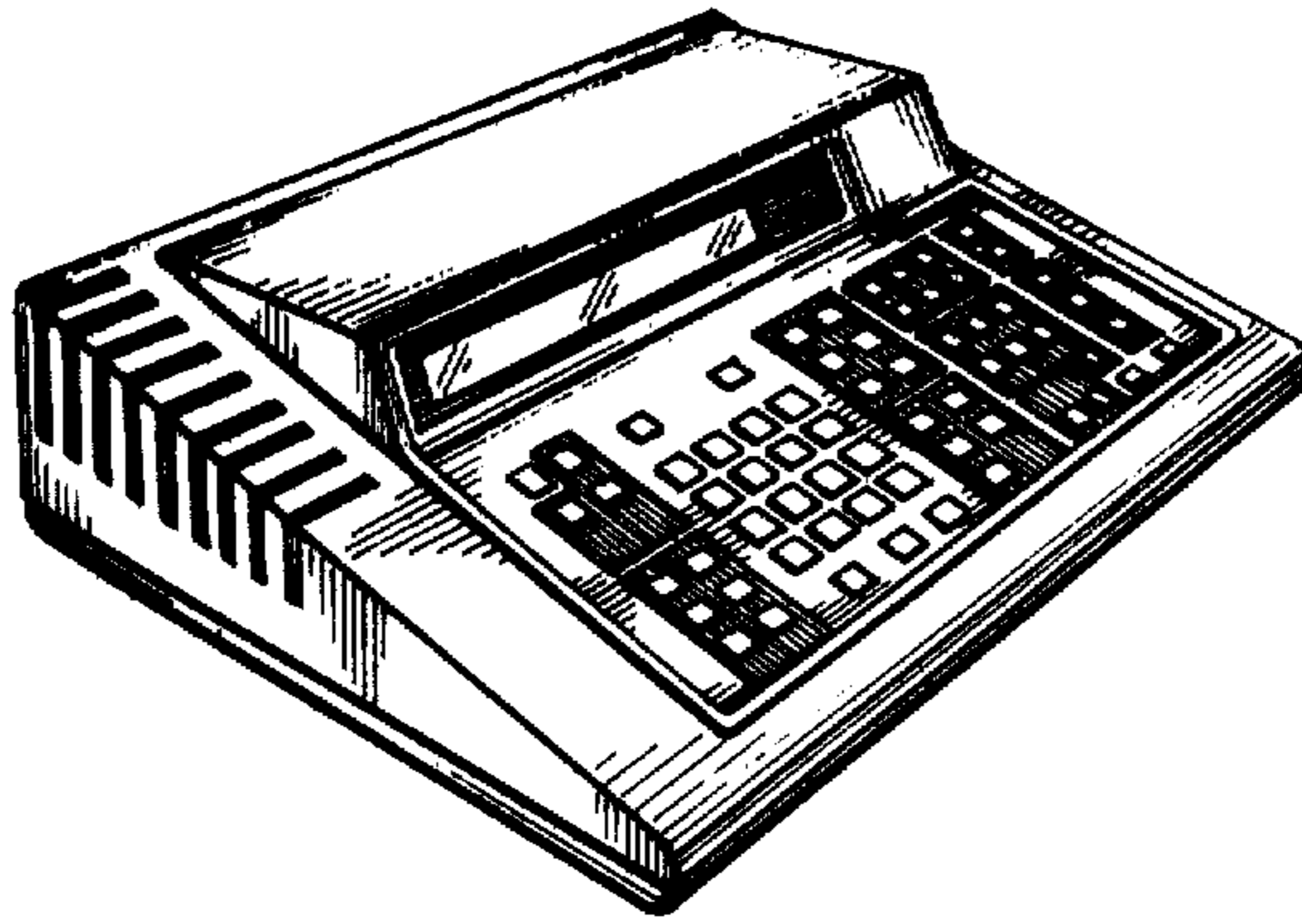


Fig. 7.

Fig. 8.

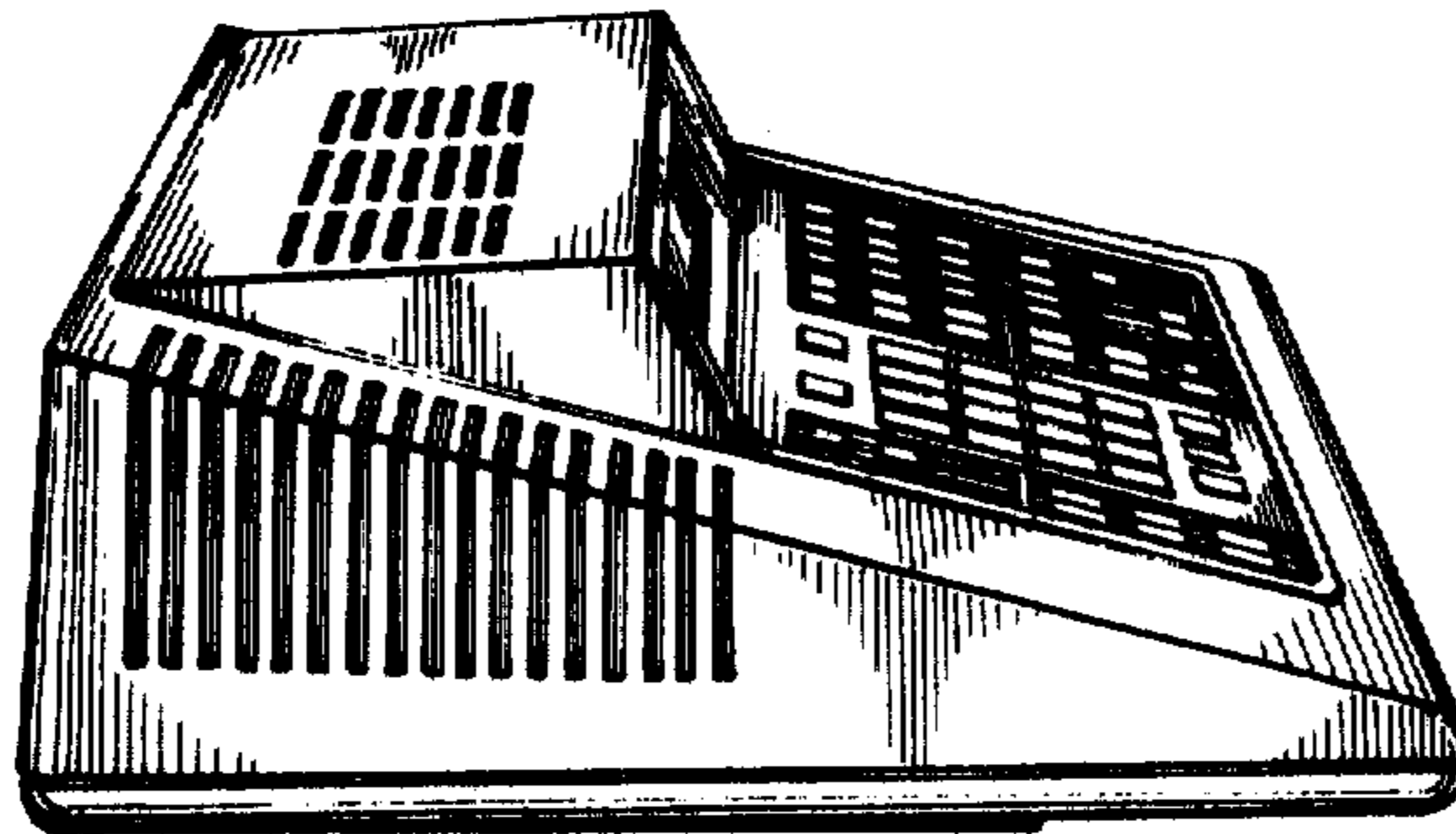
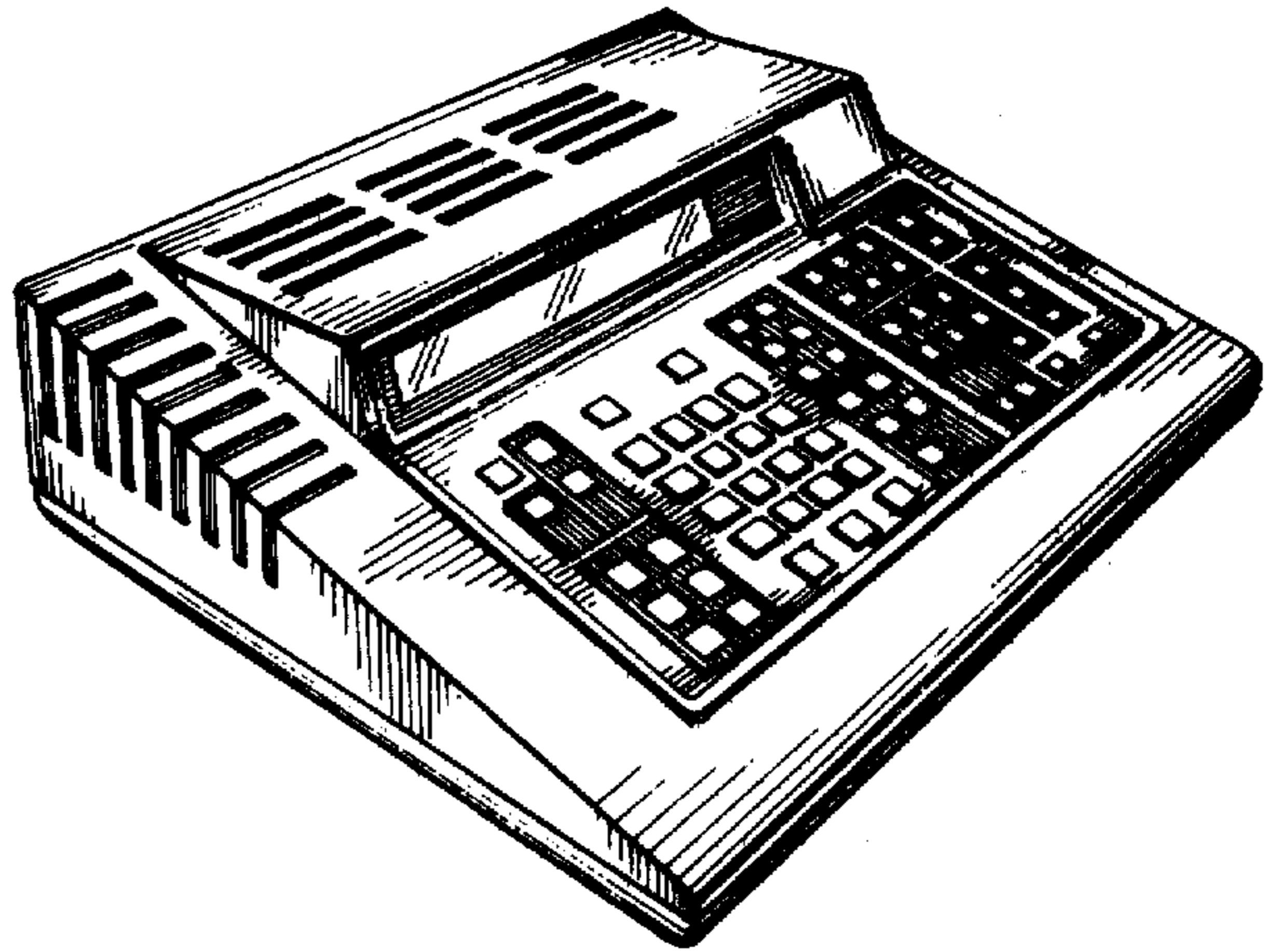


Fig. 9.